STFI26NM60N

N-channel 600 V, 0.135 Ω 20 A MDmesh™ II Power MOSFET in I²PakFP

Preliminary data

Features

Type	V_{DSS}	$R_{DS(on)}$ max	I_D
STFI26NM60N	600 V	< 0.165 Ω	20 A

■ Fully insulated and low profile package with increased creepage path from pin to heatsink plate

■ 100% avalanche tested

■ Low input capacitance and gate charge

■ Low gate input resistance

Applications

■ Switching applications

Description

This device is an N-channel Power MOSFET developed using the second generation of MDmesh™ technology. This revolutionary Power MOSFET applies a new vertical structure to the company's strip layout to yield a device with one of the world's lowest on-resistance and gate charge, making it suitable for the most demanding high-efficiency converters.
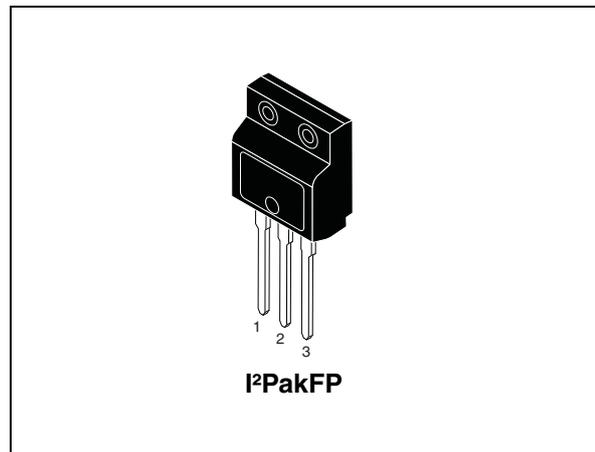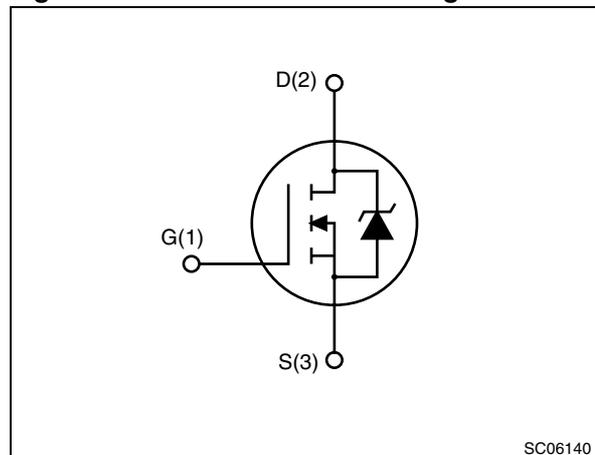

I²PakFP

Figure 1. Internal schematic diagram

SC06140

Table 1. Device summary

Order codes	Marking	Package	Packaging
STFI26NM60N	26NM60N	I²PakFP	Tube

Contents

1 Electrical ratings

Table 2.   Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	600	V
V_{GS}	Gate-source voltage	± 25	V
I_D	Drain current (continuous) at $T_C = 25$ °C	20[1]	A
I_D	Drain current (continuous) at $T_C = 100$ °C	12.6 [1]	A
I_{DM} [2]	Drain current (pulsed)	80[1]	A
P_{TOT}	Total dissipation at $T_C = 25$ °C	30	W
	Derating factor	0.24	W/°C
dv/dt [3]	Peak diode recovery voltage slope	15	V/ns
V_{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t=1 s;T_C=25 °C)	2500	V
T_{stg}	Storage temperature	- 55 to 150	°C
T_j	Max. operating junction temperature	150	°C

1. Limited only by maximum temperature allowed.

2. Pulse width limited by safe operating area .

3. $I_{SD} \leq 20$ A, di/dt ≤ 400 A/µs, $V_{DSpeak} \leq V_{(BR)DSS}$, $V_{DD} = 80\%$ $V_{(BR)DSS}$

Table 3.   Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	4.17	°C/W
$R_{thj-amb}$	Thermal resistance junction-ambient max	62.5	°C/W
T_l	Maximum lead temperature for soldering purpose	300	°C

Table 4.   Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AS}	Avalanche current, repetitive or not-repetitive (pulse width limited by Tj max)	6	A
E_{AS}	Single pulse avalanche energy (starting T_J=25 °C, I_D=I_{AS}, V_{DD}=50 V)	610	mJ

2 Electrical characteristics

(T_{CASE} = 25 °C unless otherwise specified)

Table 5. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	I_D = 1 mA, V_{GS} = 0	600			V
I_{DSS}	Zero gate voltage drain current (V_{GS} = 0)	V_{DS} = 600 V V_{DS} = 600 V, T_C= 125 °C			1 100	µA µA
I_{GSS}	Gate-body leakage current (V_{DS} = 0)	V_{GS} = ± 25 V			± 0.1	µA
$V_{GS(th)}$	Gate threshold voltage	V_{DS} = V_{GS}, I_D = 250 µA	2	3	4	V
$R_{DS(on)}$	Static drain-source on resistance	V_{GS} = 10 V, I_D = 10 A		0.135	0.165	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss} C_{oss} C_{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V_{DS} = 50 V, f = 1 MHz, V_{GS} = 0	-	1800 115 1.1	-	pF pF pF
$C_{oss\ eq.}$ [(1)]	Equivalent output capacitance	V_{GS} = 0, V_{DS} = 0 to 480 V	-	310	-	pF
Q_g Q_{gs} Q_{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} = 480 V, I_D = 20 A, V_{GS} = 10 V, *(see Figure 15)*	-	60 8.5 30	-	nC nC nC
R_g	Gate input resistance	f=1 MHz gate DC Bias=0 test signal level = 20 mV open drain	-	2.8	-	Ω

1. $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DS}

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	Turn-on delay time Rise time Turn-off delay time Fall time	V_{DD} = 300 V, I_D = 10 A R_G = 4.7 Ω V_{GS} = 10 V *(see Figure 14)*	-	13 25 85 50	-	ns ns ns ns

Table 8.   **Source drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD} I_{SDM} [1]	Source-drain current Source-drain current (pulsed)		-		20 80	A A
V_{SD} [2]	Forward on voltage	I_{SD} = 20 A, V_{GS} = 0	-		1.5	V
t_{rr} Q_{rr} I_{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD} = 20 A, di/dt = 100 A/µs V_{DD} = 60 V *(see Figure 16)*	-	370 5.8 31.6		ns µC A
t_{rr} Q_{rr} I_{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD} = 20 A, di/dt = 100 A/µs V_{DD} = 60 V, T_j = 150 °C *(see Figure 16)*	-	450 7.5 32.5		ns µC A

1. Pulse width limited by safe operating area

2. Pulsed: pulse duration = 300 µs, duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2.   Safe operating area
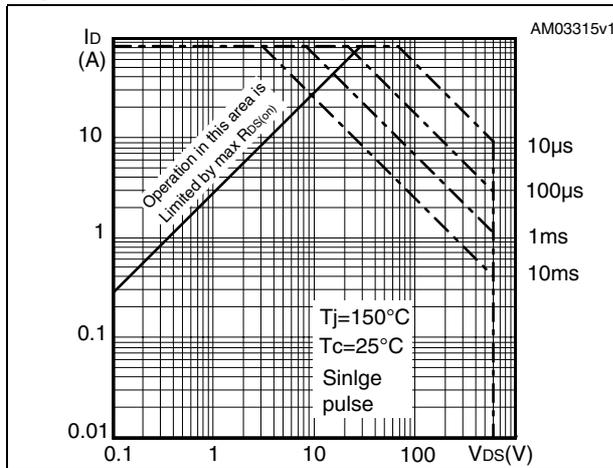
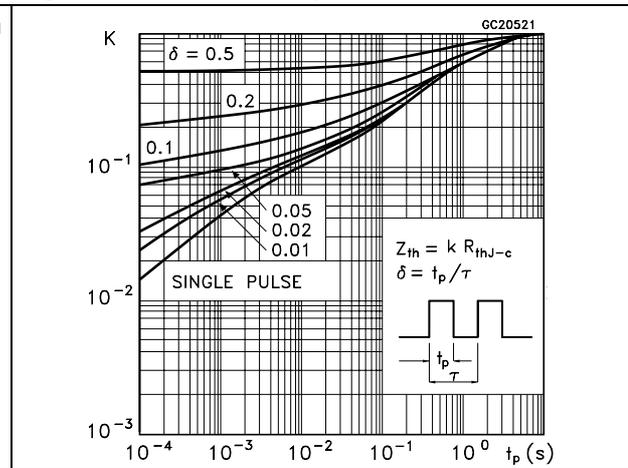Figure 3.   Thermal impedance
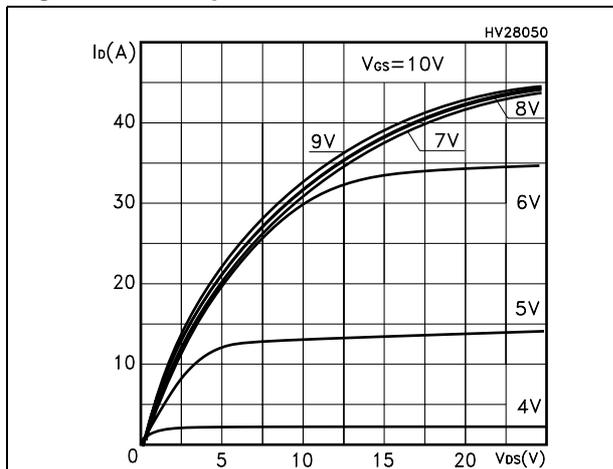

Figure 4.   Output characteristics

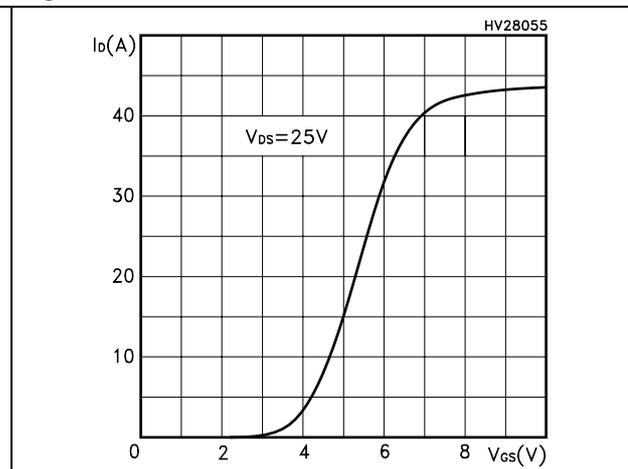Figure 5.   Transfer characteristics

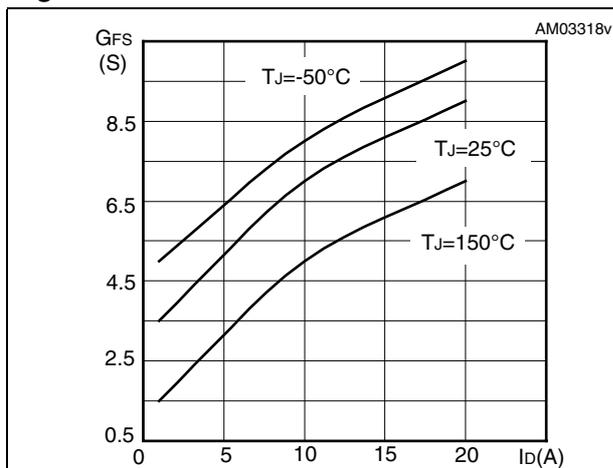Figure 6.   Transconductance

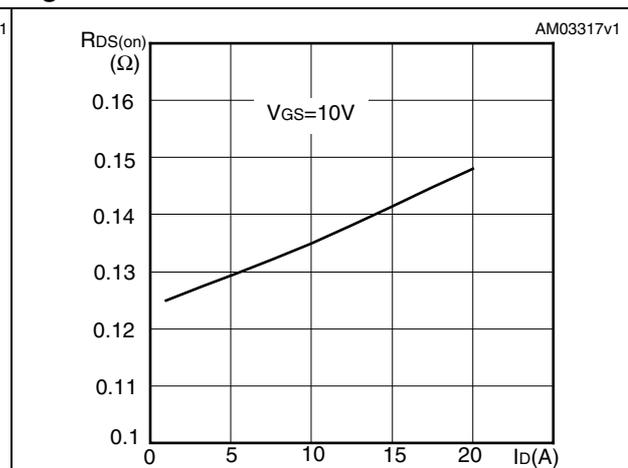Figure 7.   Static drain-source on resistance

Figure 8.   Gate charge vs gate-source voltage
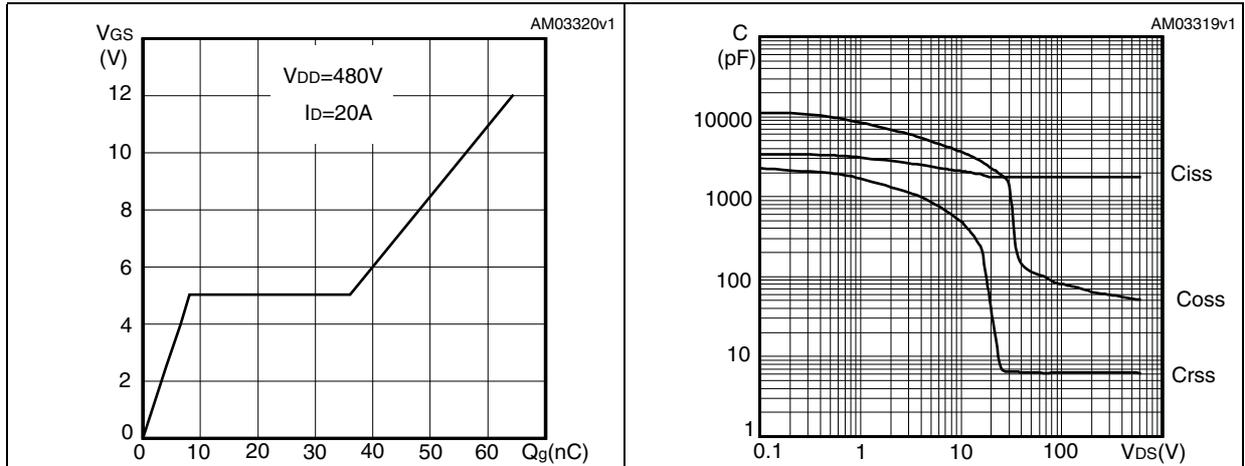

Figure 9.   Capacitance variations

Figure 10.   Normalized gate threshold voltage vs temperature

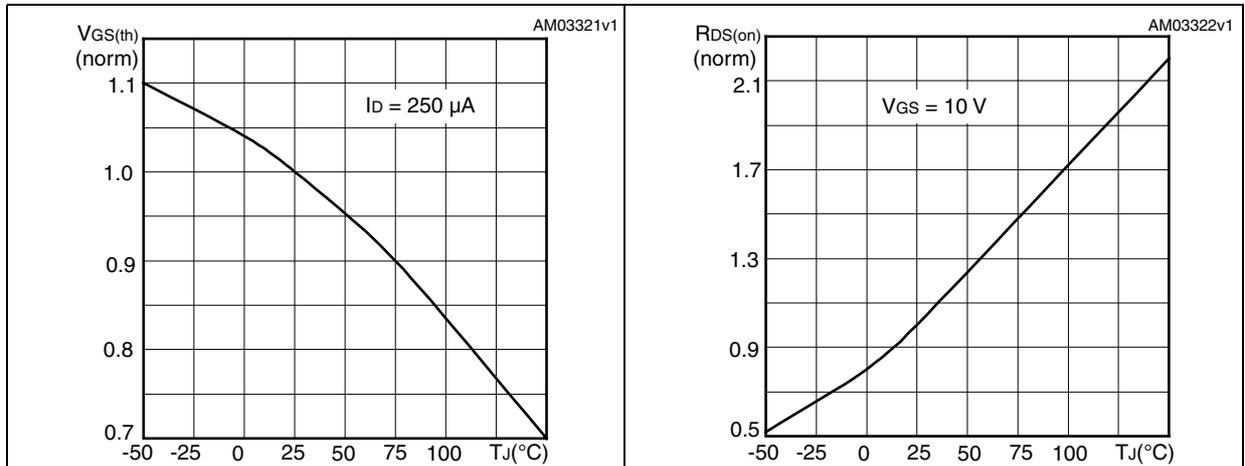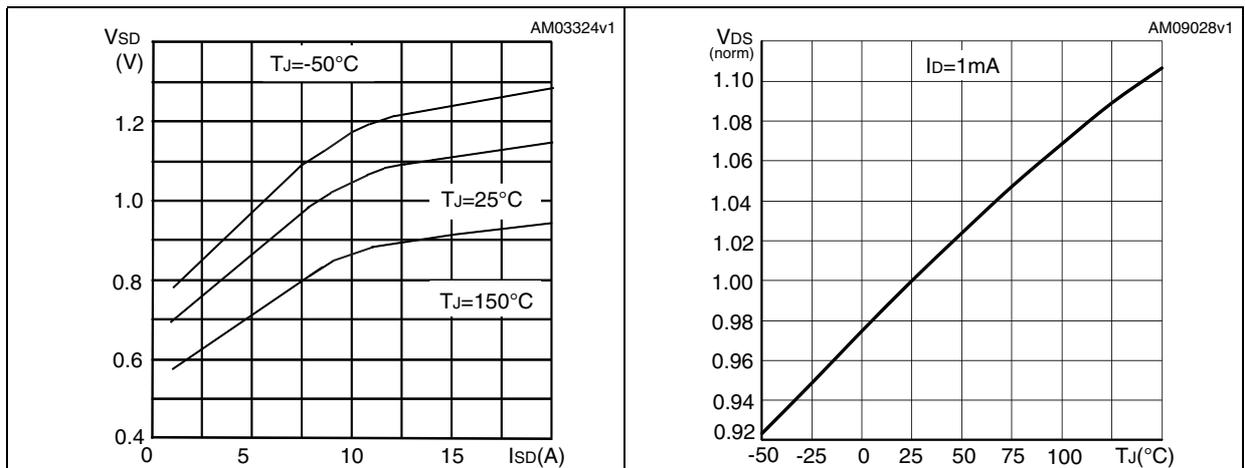**Figure 11.   Normalized on resistance vs temperature**

Figure 12.   Source-drain diode forward characteristics

Figure 13.   Normalized V_{DS} vs temperature

3   Test circuits
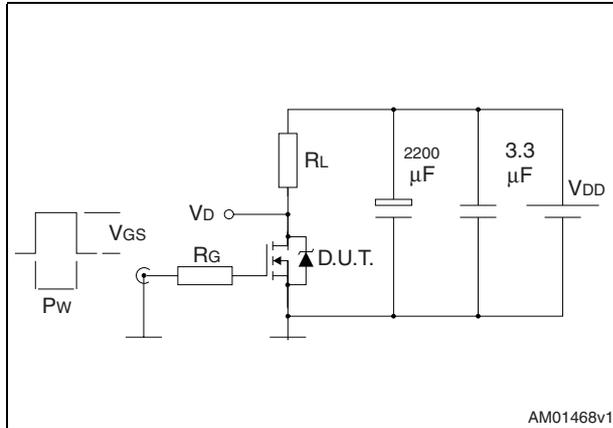
Figure 14.   Switching times test circuit for resistive load
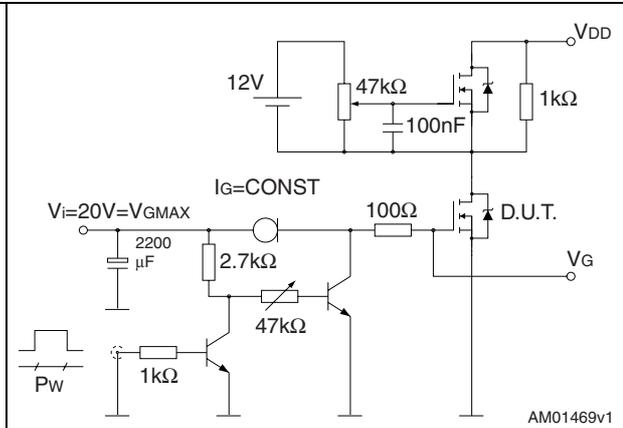

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Figure 15.   Gate charge test circuit

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Figure 16.   Test circuit for inductive load switching and diode recovery times
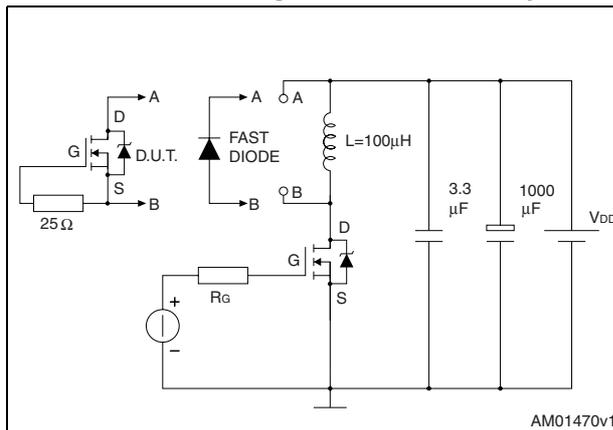

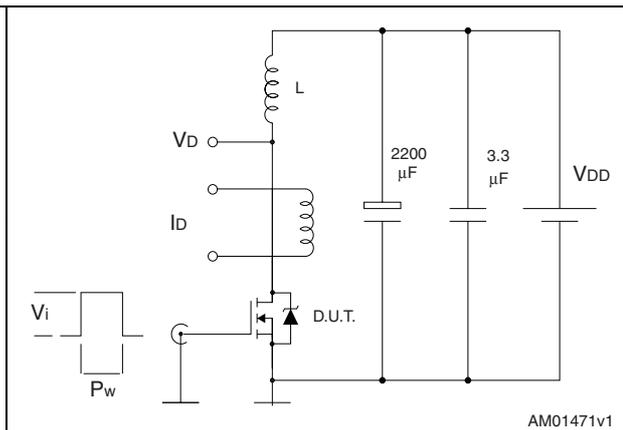AM01470v1

Figure 17.   Unclamped inductive load test circuit

AM01471v1

Figure 18.   Unclamped inductive waveform
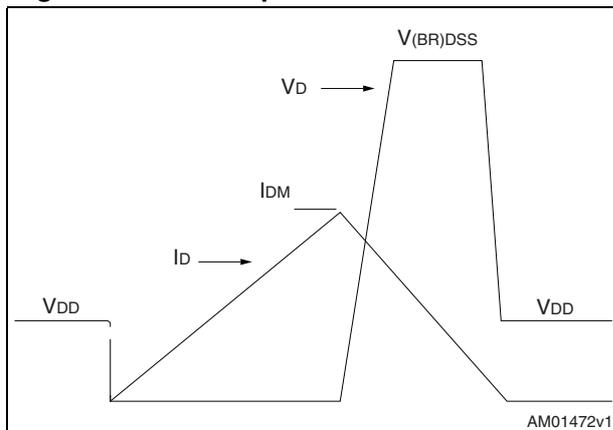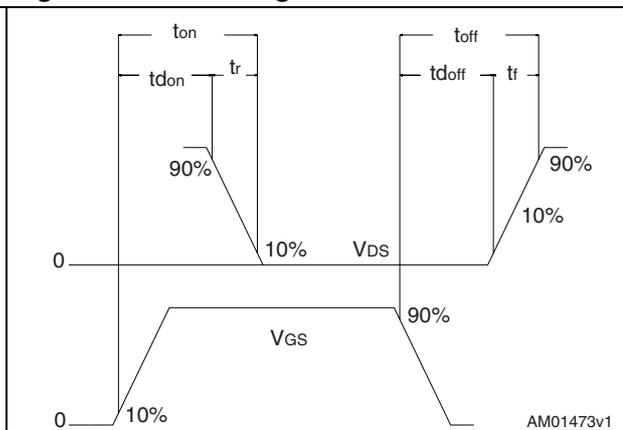

AM01472v1

Figure 19.   Switching time waveform

AM01473v1

4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK$^®$ packages, depending on their level of environmental compliance. ECOPACK$^®$ specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

Table 9. I²PakFP mechanical data

Dim.	mm		
	Min.	**Typ.**	**Max.**
A	4.40		4.60
B	2.50		2.70
D	2.50		2.75
D1	0.65		0.85
E	0.45		0.70
F	0.75		1.00
F1			1.20
G	4.95	-	5.20
H	10.00		10.40
L1	21.00		23.00
L2	13.20		14.10
L3	10.55		10.85
L4	2.70		3.20
L5	0.85		1.25
L6	7.30		7.50

Figure 20. I²PakFP drawing
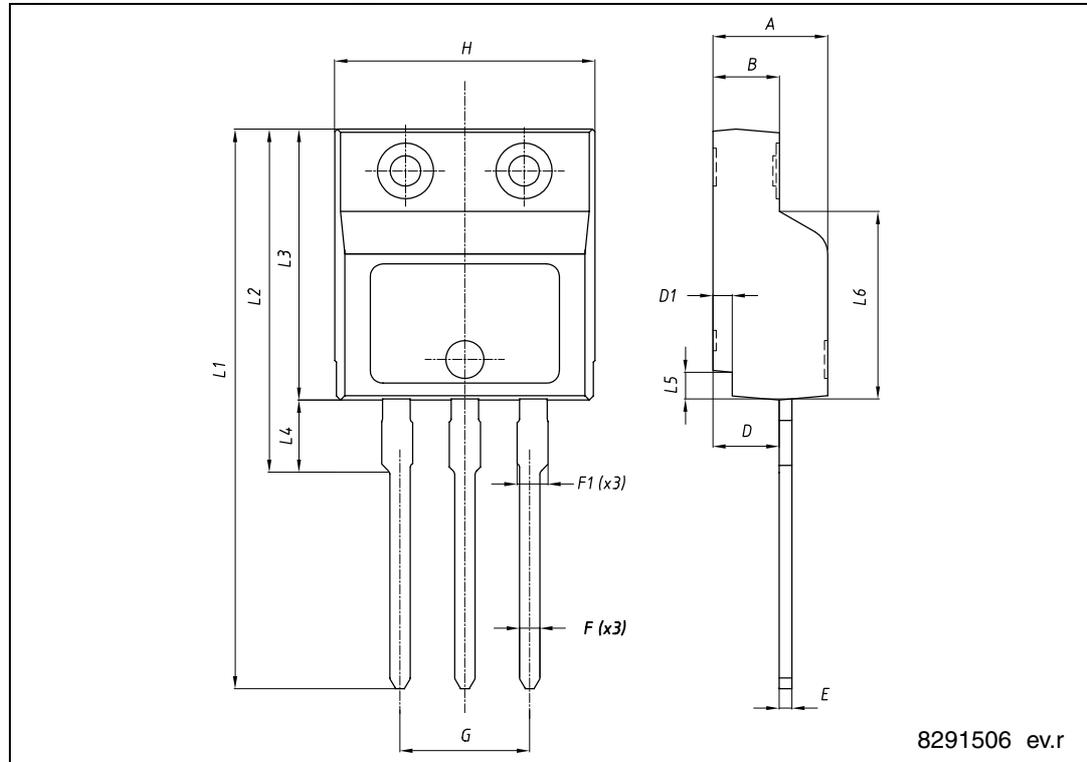
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5   Revision history

Table 10.   Document revision history

Date	Revision	Changes
15-Nov-2011	1	First release.

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